



# Non-linear response of an electrode–electrolyte interface impedance with the frequency

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## Abstract

In this paper we analyze the frequency response of a distributed parameters non-linear circuit. This circuit is a fractal model of an electrode–electrolyte interface. The results show that the series equivalent resistance  $R_{eq}$  decreases as the number of fractal levels rises. Its frequency behavior is similar to the results described by other authors that used a constant phase angle element. At low frequency range, the series equivalent reactance  $X_{eq}$  decreases with frequency and  $R_{eq}$  shows a flat response in this range. The model also explains how interface geometry modifies the values of some electrochemical parameters. As roughness increases the Argand diagram shows smaller semicircles. The model behavior is like a single dispersion system with its central frequency increasing with the electrode roughness.

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## 1. Introduction

Frequency dependence of an electrode impedance is not a new phenomenon. The electrode–electrolyte interface (EEI) was studied at low [1–10] and at high current density [7,11–13]. In non-linear dielectric spectroscopy of biological suspensions, the way EEI distorts the biological non-linearities was poorly studied [14–16].

A new EEI model which integrate in the same electrical circuit, electrochemical and geometrical features of an electrode, was presented previously in one of our papers. [13]. This model allows to predict qualitatively the EEI behavior at high and low current density and at constant frequency. The frequency response of the model above is presented in this paper.

Our results show that the series equivalent resistance  $R_{eq}$  of the circuit decreases when the number of fractal levels considered increases, and its frequency behavior is qualitatively similar to those reported by other authors [4,6,17] within the frequency ranges analyzed.

There is a significant similarity between our results and those presented by authors who used a constant phase angle (CPA) element [4,5,7,10,11] in their models.

The series equivalent reactance  $X_{eq}$  shows a *bell-like* behavior when the frequency decreases within the range analyzed, whereas  $R_{eq}$  shows a typical *sigmoid* curve. The model behave as if it were a single dispersion system. This also explains how the interface roughness might affect the quantification of pure electrochemical parameters.

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## 2. Interfaces modelling

### 2.1. EEI fractal model

EEI was modeled as an electrical circuit originated in the geometrical structure of a fractal net, which includes two electrochemical parameters, the double layer capacity  $C_{dl}$  and the charge transfer resistance  $R_{ct}$  in parallel with  $C_{dl}$  as it is shown in Fig. 1 [13].

It is supposed that the charge transfer process is controlled by activation (neither the diffusion effects nor the mass transport by migration or convection are considered), in each electrochemical reaction one electron is transferred, and the corrosion or superficial adsorption processes are not considered either in order to simplify the procedure.

In Fig. 1 the value of the capacity and the charge transfer resistance of each level is obtained with the following equations:

$$C_{dlj} = 2^j C_{dl} \tag{1}$$

$$R_{ctj}(\eta_j) = \frac{1}{2^j J_0 \frac{F}{\mathfrak{R}T} \left( (1 - \beta_c) \exp \left[ \frac{(1 - \beta_c) F \eta_j}{\mathfrak{R}T} \right] + \beta_c \exp \left[ \frac{-\beta_c F \eta_j}{\mathfrak{R}T} \right] \right)} \tag{2}$$

where  $J_0$  is the exchange current density,  $F$  is the Faraday constant,  $\mathfrak{R}$  is the universal gas constant,  $T$  is the absolute temperature,  $\beta_c$  is the cathodic transfer coefficient and  $j$  is the fractal level. If  $j$  is the 0 (fractal level 0) correspond to a flat electrode.

### 3. Series equivalent resistance and reactance for an EEI model of two fractal levels

The equivalent impedance for an EEI geometric model of two fractal levels is shown in Eq. (3),

$$Z_{eq} = R + \frac{Z_0 \left( \frac{aR}{2} + \frac{Z_1 \left( \frac{a^2 R}{4} + Z_2 \right)}{Z_1 + \frac{a^2 R}{4} + Z_2} \right)}{Z_0 + \frac{aR}{2} + \frac{Z_1 \left( \frac{a^2 R}{4} + Z_2 \right)}{Z_1 + \frac{a^2 R}{4} + Z_2}} \tag{3}$$

where  $Z_j$  is a parallel between  $R_{ctj}$  and  $C_{dlj}$  and it is supposed that the apparent area of the working electrode is  $1 \text{ cm}^2$ , and  $i = \sqrt{-1}$ . The qualitative behavior with more levels is similar, and it does not contribute significantly to the understanding of the subject.

Finally,

$$R_{eq} = \text{Re}(Z_{eq}) \tag{4}$$

$$X_{eq} = \text{Im}(Z_{eq}) \tag{5}$$

### 4. Temporal evolution of $R_{eq}$ and $X_{eq}$ for an altern overpotential

When an altern overpotential  $\eta_{in}$  is applied on the interface (Eq. (6)), the overpotentials  $\eta_j$ , as well as  $R_{ctj}$  and  $C_{dlj}$ , with  $j = 0, 1$  and  $2$ , will also show periodical temporal behavior.

$$\eta_{in} = \eta_{in}^0 \sin(2\pi ft) \tag{6}$$

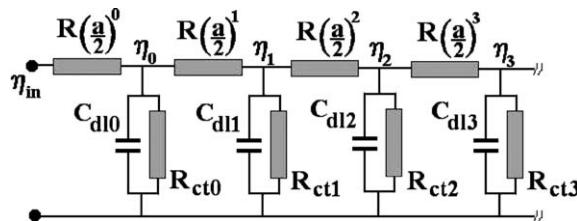


Fig. 1. Simplified fractal net of four branches showing the first fractals levels.  $R$ : electrolytical resistance,  $a$ : scale factor,  $\eta_{0,1,2,3}$ : overpotentials at different fractal levels.

In order to study the temporal evolution of  $R_{\text{eq}}$  and  $X_{\text{eq}}$ , the second Kirchoff's Law is applied (Eq. (7)) to the first node of the net in Fig. 1.

$$I_0 = I_1 + I_{R_{\text{ct}0}} + I_{C_{\text{dl}0}} \quad (7)$$

Given that

$$I_{C_{\text{dl}0}} = C_{\text{dl}0} \frac{d\eta_0}{dt} \quad (8)$$

It is obtained

$$\frac{d\eta_0}{dt} = \frac{\eta_{\text{in}}}{R} - \eta_0 \left( \frac{1}{R} + \frac{1}{R_{\text{ct}0}} + \frac{2}{aR} \right) + \frac{2\eta_1}{aR} \quad (9)$$

By repeating the procedure on the next two nodes in the Fig. 1, the following expressions are obtained:

$$\frac{d\eta_1}{dt} = \frac{2\eta_0}{aR} - \eta_1 \left( \frac{2}{aR} + \frac{1}{R_{\text{ct}1}} + \frac{4}{a^2R} \right) + \frac{4\eta_2}{a^2R} \quad (10)$$

$$\frac{d\eta_2}{dt} = \frac{4\eta_1}{a^2R} - \eta_2 \left( \frac{4}{a^2R} + \frac{1}{R_{\text{ct}2}} \right) \quad (11)$$

Since  $R_{\text{ct}j}$  depend on the overpotentials  $\eta_j$ , Eqs. (9)–(11) are a differential equations system, which can not be solved analytically. Therefore, numerical method was applied and a simple algorithm was implemented in *Mathematica*.

## 5. Algorithm to obtain $R_{\text{eq}}$ and $X_{\text{eq}}$

We started setting the values for  $J_0$ ,  $K = F/(\mathfrak{RT})$ ,  $\beta_c$ ,  $a$ ,  $R$ ,  $\Delta t$ ,  $f$ ,  $f_{\text{max}}$ ,  $\Delta f$ ,  $C_{\text{dl}}$  and  $\eta_{\text{in}}^0$ , and setting zero time  $t$  and overpotentials  $\eta_0$ ,  $\eta_1$  y  $\eta_2$ . Besides, at  $t = 0$ ,  $\eta_{\text{in}} = 0$  and  $\eta_j = 0$  where  $j = 0, 1$  and  $2$ . With the previously defined values,  $R_{\text{ct}j}$  was calculated using Eq. (2), and  $d\eta_j/dt$  using Eqs. (9)–(11).  $R_{\text{eq}}$  and  $X_{\text{eq}}$  were computed with the Eqs. (4) and (5) and they were saved into a data file including the initial values of  $\eta_j$ ,  $R_{\text{ct}j}$ ,  $d\eta_j/dt$ ,  $R_{\text{eq}}$  and  $C_{\text{eq}}$ , at  $t = 0$ . A new iteration begins when time  $t$  and overpotential  $\eta_j$  are increased, and it is repeated until one period of the input signal is completed.

Once the cycles are completed, the Discrete Fourier Transform of  $R_{\text{eq}}$  and  $C_{\text{eq}}$  is calculated from the saved data, and another data file is created where the values of TDF( $R_{\text{eq}}$ ) and TDF( $C_{\text{eq}}$ ) are also saved, with the corresponding values of  $f$  and  $\eta_{\text{in}}^0$ . Then the program increase the frequency in  $\Delta f$  and it repeats the process above. Afterthat, the process is carried out again for other  $\eta_{\text{in}}^0$  values.

For the simulation typical values of the parameters were used:  $\beta_c = 0.5$ ,  $T = 298$  K,  $f = 1 \times 10^{-3}$  Hz,  $f_{\text{max}} = 10^4$  Hz,  $\eta_{\text{in}}^0 = 22$  mV,  $R = 100$   $\Omega$ ,  $a = 4$ ,  $C_{\text{dl}} = 1 \times 10^{-5}$  F,  $J_0 = 2.1 \times 10^{-5}$  A/cm<sup>2</sup>.

The  $\Delta f$  value chosen produced an uniform distribution of points in a logarithm scale.

With these values, the charge time of the capacitors is in the order of  $10^{-3}$  s. For frequencies lower than  $10^2$  Hz the transient is negligible and a single input cycle is enough for the analysis. For frequencies higher than  $10^4$  Hz, the transient last 5 cycles, that is why 30 cycles were used for the averaging.

## 6. Materials and methods

In order to validate the proposed model, several experiments were carried out so as to study the ZIEE behavior with the frequency, at constant overpotential and using polished electrodes with sandpaper of different granulations.

The measurement cell (Fig. 2) is made of acrylic and it allows us to carry out tripolar measurements. The three electrodes are made of stainless steel DENTAURUM®. The working electrode (WE) is a solid cylinder (1.5 cm long), and only 1 cm<sup>2</sup> of its transversal section is exposed, the rest was insulated with grilon.

The counter electrode (CE) is semi circular and it was made with an area larger than the working electrode in order to minimize its impedance (70 cm<sup>2</sup>). The reference electrode is 1 mm in diameter and only 1 mm is exposed at its end, the rest is covered with a glass sealed capillary. The measurements were carried out with the Solartron® system 12508 W which includes a Frequency Response Analyzer 1250 and an electrochemical interface 1287. The data

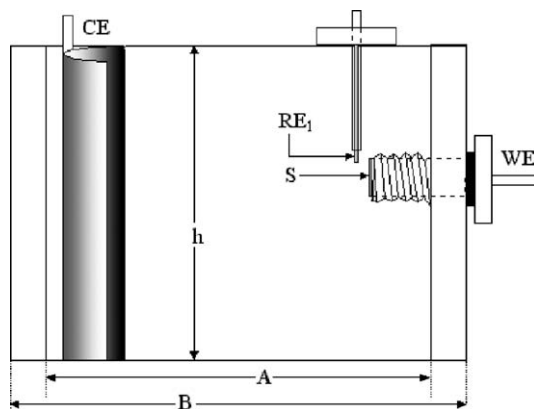


Fig. 2. Lateral view of the measurement cell.  $A = 10.0$  mm,  $B = 11.8$  mm,  $h = 8.4$  mm,  $S = 1$  cm<sup>2</sup>.

Table 1  
Steps for polishing electrodes

	Step 1	Step 2	Step 3	Final roughness ( $\mu\text{m}$ )
Electrode 1	sandpaper # 180 AcquaFlex®	sandpaper # 240 Carbimet®	sandpaper # 600 Carbimet®	25.80
Electrode 2	sandpaper # 180 AcquaFlex®	sandpaper # 240 Carbimet®		58.50
Electrode 3	sandpaper # 180 AcquaFlex®			78.00

The size of the grain matches the European standards FEPA standard 43-GB-1984 (R1993).

visualization and processing were carried out with the commercial systems Zplot® and Zview® of Solartron. The electrodes were polished in gradual steps and with different roughness degrees according to the diagram indicated in Table 1.

Overpotentials with frequencies within the interval of 0.01 to 65,000 Hz were applied with the Solartron system.

The sampling frequency was such that the measurements points were equally spaced in a logarithmic scale taking 10 points per decade. The integration time of the measurements was of 1 cycle for frequencies lower than 1 Hz and 16 cycles for the rest.

In every case, the potential was stabilized in open circuit until the voltage shift was lower than 0.05 mV/seg; then the equivalent series resistance and reactance measurements were carried out. The overpotentials used were 5, 20 and 50 mV. The working solution used was NaCl 0.9%.

## 7. Results

### 7.1. Theoretical

#### 7.1.1. $R_{eq}$ and $X_{eq}$ as a function of the ac overpotential frequency

Fig. 3 shows the average temporal value of  $R_{eq}$  (a) and  $X_{eq}$  (b) as a function of the frequency of the overpotential applied, for three nets and each one corresponding to a different fractal level ( $j = 0, 1, 2$ ). These values are evaluated through the DC components of the Fourier spectrum DFT(dc) of the  $R_{eq}$  and  $X_{eq}$  curves for each frequency. Fig. 3 also shows a single frequency dispersion  $f_0$ , where  $X_{eq}$  presents a maximum, and this frequency  $f_0$  increases with the increment of the interface roughness.

Another way to show the results of Fig. 3 is to represent  $-iX_{eq}$  as a function of  $R_{eq}$  for each one of the frequencies (Argand diagram). This is shown in Fig. 4. The circular fitting of the rough electrodes, produces depressed semi-circular arc whose center lies below the real axis.

These fitting are not shown in order to clarify the figure. The flat electrode does not show any depression in the center of the circle, this event is well described in the literature of disperse systems [4,5]. When the roughness increases,

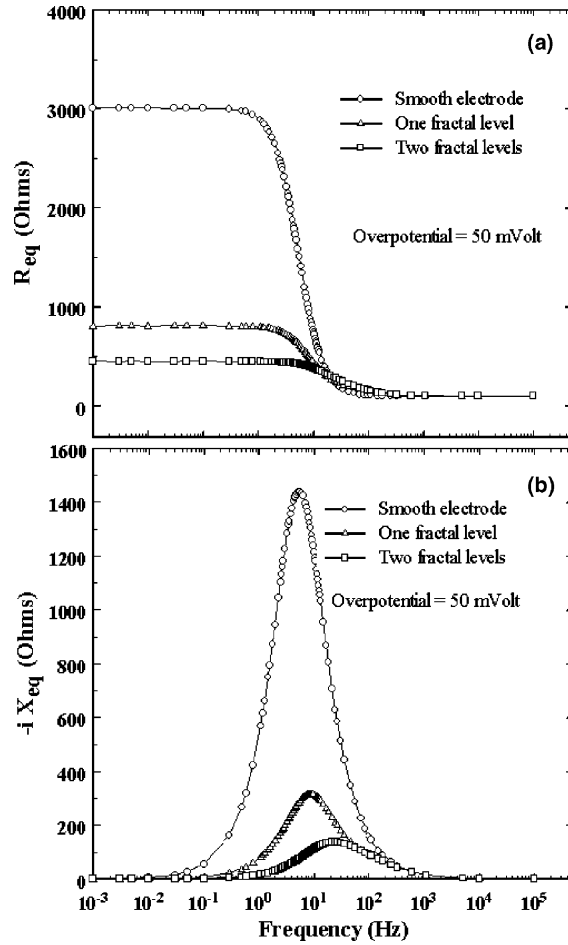


Fig. 3.  $R_{eq}$  and  $X_{eq}$  as a function of the frequency for three different fractal nets: a flat electrode and two rough electrodes.  $\beta_c = 0.5$ ,  $T = 298$  K,  $R = 100 \Omega$ ,  $a = 4$ ,  $C_{dl} = 1 \times 10^{-5}$  F.

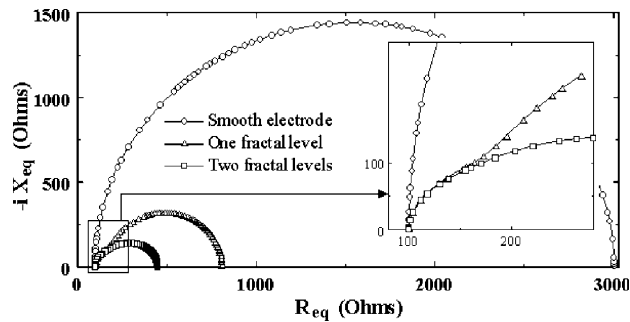


Fig. 4. Argand Diagram of the EEI for flat, one and two fractal levels electrodes.  $\beta_c = 0.5$ ,  $T = 298$  K,  $R = 100 \Omega$ ,  $a = 4$ ,  $C_{dl} = 1 \times 10^{-5}$  F. Overpotential = 50 mV.

the semicircles get distorted and become smaller. When rough electrodes are used, at high frequencies, the points can be adjusted to a depressed semi-circular arc equivalent to the fractal circuit without  $R_{ct}$ . This may be appreciated in the inset of Fig. 4.

## 7.2. Experimental

The behavior of the resistance and the reactance as a function of the frequency of the three roughnesses is presented in Figs. 6 and 7. These diagrams are parametric in roughness. Fig. 6 shows the behavior of XR of the different electrodes. The inset shows a detail of the curve at high frequencies. It is observed that the semicircle is much smaller for the electrode with a higher roughness.

It is possible to define an apparent charge transfer resistance  $R_{cta}$ , and a double layer apparent capacity  $C_{dla}$ , similar to the ones of a flat electrode.  $R_{cta}$  is calculated from the XR diagram as the diameter of the semicircle.  $C_{dla}$  is deduced using  $R_{cta}$  and  $f_0$  from Eq. (12).

$$C_{dla} = \frac{1}{2\pi f_0 R_{cta}} \quad (12)$$

Fig. 7a shows the behavior of  $R_{eq}$  versus frequency and Fig. 7b shows the one of  $X_{eq}$  versus frequency. The results show that we have only reached the beginning of the low frequency plateau only in the case of the electrode of higher roughness. The peak of  $X_{eq}$  curve matches the 50% of the maximum amplitude of the corresponding  $R_{eq}$  curve, for the electrode polished at 78  $\mu\text{m}$ .

The data obtained were not enough to reach the plateau for the rest of the electrodes, but we can deduce from the curves, that the plateau will be placed in a lower frequency range.

## 8. Discussion and conclusions

A phenomenological circuit model has been used instead of *black box* model, because it allows us to interpret better the physical processes involved in the system. Therefore, each component has its specific physical interpretation.

The double layer charge can be interpreted as a molecular capacitor, where one plate is represented by the charges on the metal and the other by the ions at a minimum distance in the solution. The charge transfer process can be modulated as a variable electrical resistance, which depends on the overpotential applied to the interface.

The electrolytical channels of the fractal structure can be modulated according to several authors [13,19–25,20,26] as resistive elements.

The electrical model analysed is simple, it does not use idealized components without an specific physical interpretation as the constant phase angle element (CPA), and it reflects qualitatively the experimental results of other authors.

An important and well known aspect is that the geometry and the electrochemical processes are not independent. The current flow through the interface produces a potential drop which depends of the fractal level depth [26]. This

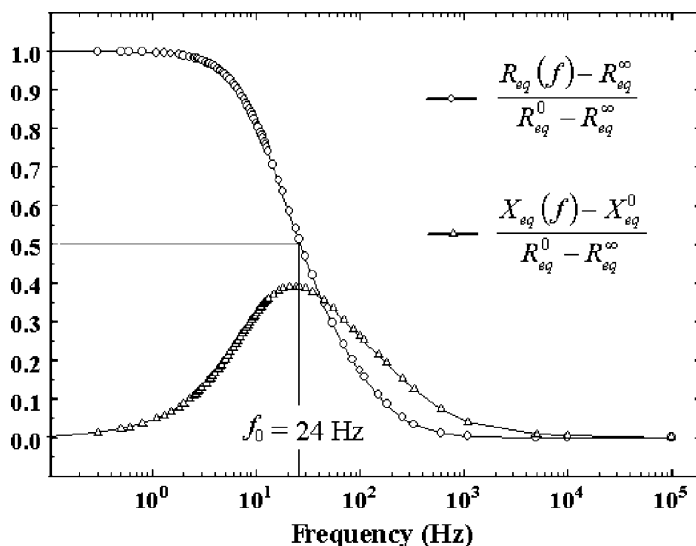


Fig. 5. Normalized  $R_{eq}$  and  $X_{eq}$  versus frequency for rough electrode modeled with two fractal levels.  $R_{eq}^{\infty}$  is the value of  $R_{eq}$  for  $f \rightarrow \infty$ ,  $R_{eq}^0$  is the value of  $R_{eq}$  for  $f \rightarrow 0$  and  $f_0$  is the frequency where  $X_{eq}$  presents a maximum.  $\beta_c = 0.5$ ,  $T = 298$  K,  $R = 100 \Omega$ ,  $a = 4$ ,  $C_{dl} = 1 \times 10^{-5}$  F and  $\eta_{in}^0 = 50$  mV.

fact is also evident in this paper since it affects the  $R_{ct}$  behavior, because it has different values depending on the fractal level analysed, as it is shown in Fig. 5 of the reference [13].

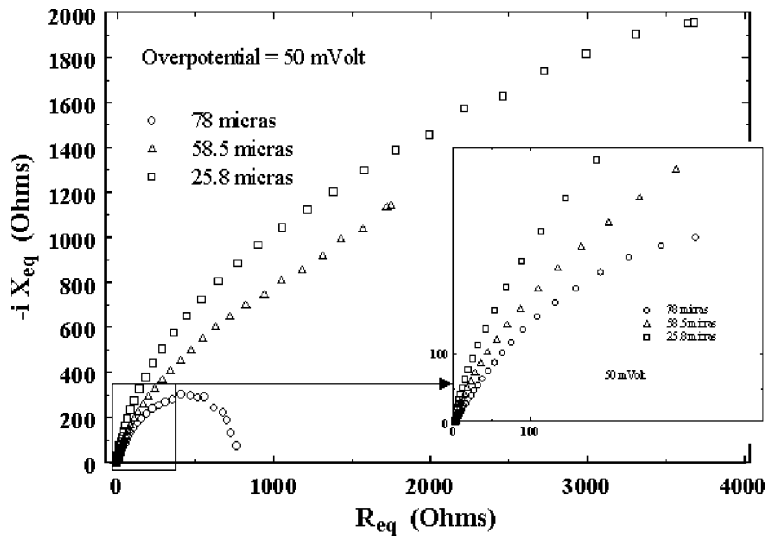


Fig. 6. Argand diagram of the EEI for AISI 304 stainless steel electrodes polished at different roughness degrees. Frequency range: 0.01 Hz–65 kHz.

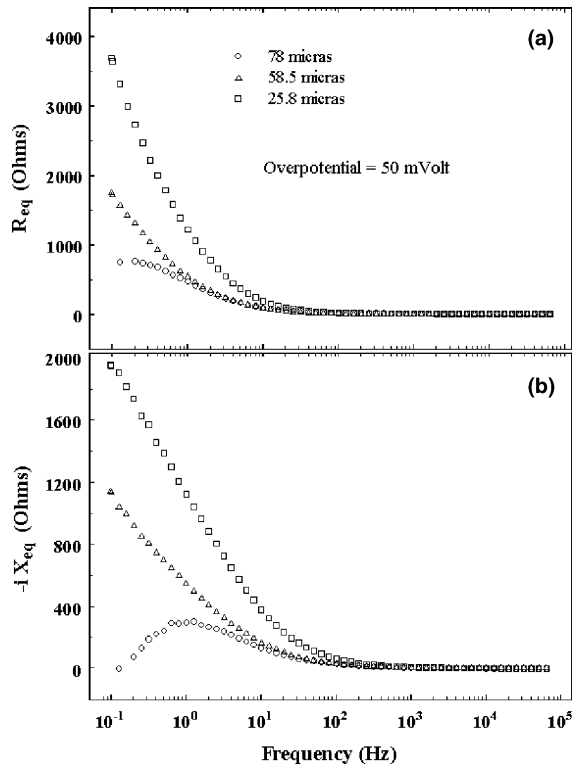


Fig. 7. Resistance (a) and reactance series equivalents (b) of the EEI versus frequency for three roughness degrees. The overpotential applied was 50 mV.

Regarding the dependence with the roughness of the impedance interface, the model predicts that, when the number of fractal levels increases (higher roughness)  $R_{eq}$  and  $X_{eq}$  decrease as it is shown in Figs. 3 and 4. It is observed qualitatively a coincidence between the behavior predicted and the experimental results (Fig. 7).

Fig. 5 shows that  $X_{eq}$  reaches the peak and  $R_{eq}$  the 50% of the maximum value when the dispersion frequency  $f_0$  occurs. This behavior could only be obtained in our experiments for the electrode polished at 78  $\mu\text{m}$ . Data at frequencies lower than 2 Hz were very hard to obtain, due to a great increase of the noise and the excessive time of the measurement which made the experimental conditions highly unstable.

The measurement noise increased particularly at low frequencies, because the integration time of each measurement had to be decreased at one cycle. When the roughness of the electrode was increased, the semicircles became smaller and  $R_{cta}$  decreased as it is shown in Fig. 4 (prediction of the model) and Fig. 6 (experimental data).

The inset of Fig. 4 shows a detail of the XR curves at high frequencies. It is possible to fit a depressed semi-circular arc in the case of rough electrodes which differs from the one made at low frequencies. This difference can be appreciated from the fact that at low frequencies,  $\frac{1}{2\pi f C_{dl}} \ll R_{ctj}$ . Therefore the original circuit can be replaced by another one without  $R_{ctj}$ .

Finally, it has to be made clear that, although this model predicts qualitatively the behaviors observed, it is still incomplete. As an example, a mass transport phenomena such as diffusion [18] which is significant at low frequencies and at high overpotentials, must be incorporated.

A quantitative prediction will be attempted in further research steps. This will also involve a deeper analysis and experimentation, because the connections between some electrochemical factors such as the current density exchange and the roughness, remain still ignored.

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